

Notice of References Cited	Application/Control No. 10/828,961	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Alpus H. Hsu	Art Unit 2665	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0081567 A1	05-2003	Okanoue et al.	370/328
*	B	US-2003/0217122 A1	11-2003	Roese et al.	709/219
*	C	US-2003/0225893 A1	12-2003	Roese et al.	709/227
*	D	US-2004/0092271 A1	05-2004	Viikari et al.	455/456.2
*	E	US-2004/0103204 A1	05-2004	Yegin, Alper E.	709/229
*	F	US-2004/0107219 A1	06-2004	Rosenberger, Joel	707/104.1
*	G	US-2004/0109429 A1	06-2004	Carter et al.	370/338
*	H	US-2004/0120323 A1	06-2004	Viikari et al.	370/395.5
*	I	US-2004/0157624 A1	08-2004	Hrastar, Scott E.	455/456.1
*	J	US-2004/0170154 A1	09-2004	Carter et al.	370/338
*	K	US-2004/0210654 A1	10-2004	Hrastar, Scott E.	709/224
*	L	US-2005/0004968 A1	01-2005	Mononen et al.	709/200
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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